

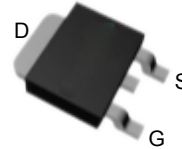
Features

- 30V/80A,
 $R_{DS(ON)} = 4\text{m}\Omega$ (typ.) @ $V_{GS} = 10\text{V}$
 $R_{DS(ON)} = 5.5\text{m}\Omega$ (typ.) @ $V_{GS} = 4.5\text{V}$
- 100% UIS + R_g Tested
- Reliable and Rugged
- Lead Free and Green Devices Available
(RoHS Compliant)
- Moisture Sensitivity Level MSL1
(per JEDEC J-STD-020D)

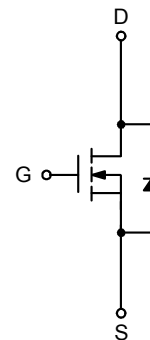
Applications

- Power Management in Desktop Computer or DC/DC Converters.

Pin Description



Top View of TO-252-2



N-Channel MOSFET

Absolute Maximum Ratings ($T_A = 25^\circ\text{C}$ Unless Otherwise Noted)

Symbol	Parameter	Rating	Unit
Common Ratings			
V_{DSS}	Drain-Source Voltage	30	V
V_{GSS}	Gate-Source Voltage	± 20	
T_J	Maximum Junction Temperature	150	$^\circ\text{C}$
T_{STG}	Storage Temperature Range	-55 to 150	$^\circ\text{C}$
I_S	Diode Continuous Forward Current	$T_C=25^\circ\text{C}$ 20	A
I_D	Continuous Drain Current	$T_C=25^\circ\text{C}$ 80 ^a	A
		$T_C=100^\circ\text{C}$ 48	
I_{DM}^b	Pulse Drain Current	$T_C=25^\circ\text{C}$ 140	A
P_D	Maximum Power Dissipation	$T_C=25^\circ\text{C}$ 50	W
		$T_C=100^\circ\text{C}$ 20	
$R_{\theta JC}$	Thermal Resistance-Junction to Case	Steady State 2.5	$^\circ\text{C/W}$
I_D	Continuous Drain Current	$T_A=25^\circ\text{C}$ 15	A
		$T_A=70^\circ\text{C}$ 12	
I_{DM}^b	Pulse Drain Current	$T_A=25^\circ\text{C}$ 60	A
P_D	Maximum Power Dissipation	$T_A=25^\circ\text{C}$ 2.1	W
		$T_A=70^\circ\text{C}$ 1.3	
$R_{\theta JA}^c$	Thermal Resistance-Junction to Ambient	$t \leq 10\text{s}$ 20	$^\circ\text{C/W}$
		Steady State 60	
I_{AS}^d	Avalanche Current, Single pulse	$L=0.5\text{mH}$ 20	A
E_{AS}^d	Avalanche Energy, Single pulse	$L=0.5\text{mH}$ 100	mJ

Note a : Max. continuous current is limited by bonding wire.

Note b : Pulse width is limited by max. junction temperature.

Note c : Surface mounted on 1in² pad area, steady state $t = 999\text{s}$.

Note d : UIS tested and pulse width are limited by maximum junction temperature 150 $^\circ\text{C}$ (initial temperature $T_J=25^\circ\text{C}$).

Electrical Characteristics ($T_A = 25^\circ\text{C}$ unless otherwise noted)

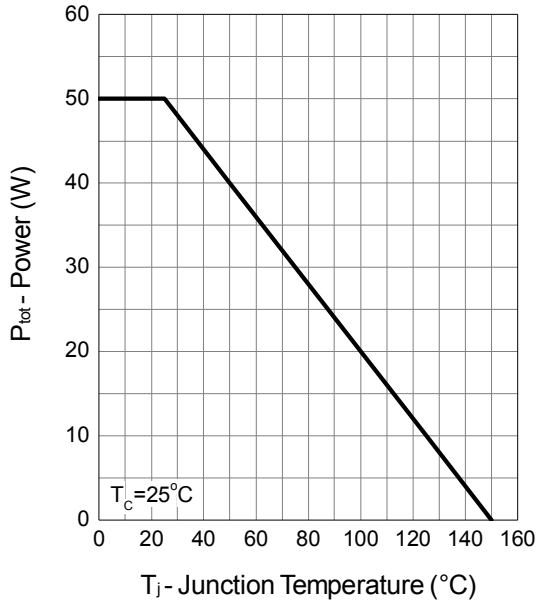
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
Static Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_{DS}=250\mu A$	30	-	-	V
$BV_{DSS(t)}$	Drain-Source Breakdown Voltage (transient)	$V_{GS}=0V, I_{D(aval)}=20A$ $T_{case}=25^\circ\text{C}, t_{transient}=100ns$	34	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{DS}=24V, V_{GS}=0V$	-	-	1	μA
		$T_J=85^\circ\text{C}$	-	-	30	
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_{DS}=250\mu A$	1.0	1.5	2.5	V
I_{GSS}	Gate Leakage Current	$V_{GS}=\pm 20V, V_{DS}=0V$	-	-	± 100	nA
$R_{DS(ON)}^e$	Drain-Source On-state Resistance	$V_{GS}=10V, I_{DS}=40A$	-	4	5.5	m Ω
		$T_J=125^\circ\text{C}$	-	5.9	-	
		$V_{GS}=4.5V, I_{DS}=20A$	-	5.5	7	
G_{fs}	Forward Transconductance	$V_{DS}=5V, I_{DS}=40A$	-	95	-	S
Diode Characteristics						
V_{SD}^e	Diode Forward Voltage	$I_{SD}=20A, V_{GS}=0V$	-	0.8	1.1	V
t_{rr}	Reverse Recovery Time	$I_{DS}=40A, di_{SD}/dt=100A/\mu s$	-	21	-	ns
t_a	Charge Time		-	13.2	-	
t_b	Discharge Time		-	7.8	-	
Q_{rr}	Reverse Recovery Charge		-	17	-	
Dynamic Characteristics^f						
R_G	Gate Resistance	$V_{GS}=0V, V_{DS}=0V, F=1MHz$	-	3	4.5	Ω
C_{iss}	Input Capacitance	$V_{GS}=0V,$ $V_{DS}=15V,$ Frequency=1.0MHz	1200	1500	1820	pF
C_{oss}	Output Capacitance		210	260	310	
C_{rss}	Reverse Transfer Capacitance		100	130	175	
$t_{d(ON)}$	Turn-on Delay Time	$V_{DD}=15V, R_L=15\Omega,$ $I_{DS}=1A, V_{GEN}=10V,$ $R_G=6\Omega$	-	15	28	ns
t_r	Turn-on Rise Time		-	13	24	
$t_{d(OFF)}$	Turn-off Delay Time		-	32	57	
t_f	Turn-off Fall Time		-	9	17	
Gate Charge Characteristics^f						
Q_g	Total Gate Charge	$V_{DS}=15V, V_{GS}=4.5V,$ $I_{DS}=40A$	-	12	17	nC
Q_g	Total Gate Charge	$V_{DS}=15V, V_{GS}=10V,$ $I_{DS}=40A$	-	25	37	
Q_{gth}	Threshold Gate Charge		-	1.5	-	
Q_{gs}	Gate-Source Charge		-	3	-	
Q_{gd}	Gate-Drain Charge		-	7.5	-	

Note e : Pulse test ; pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$.

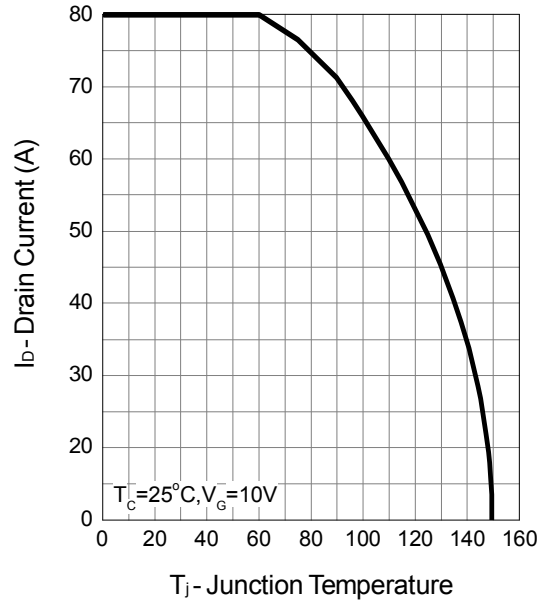
Note f : Guaranteed by design, not subject to production testing.

Typical Operating Characteristics

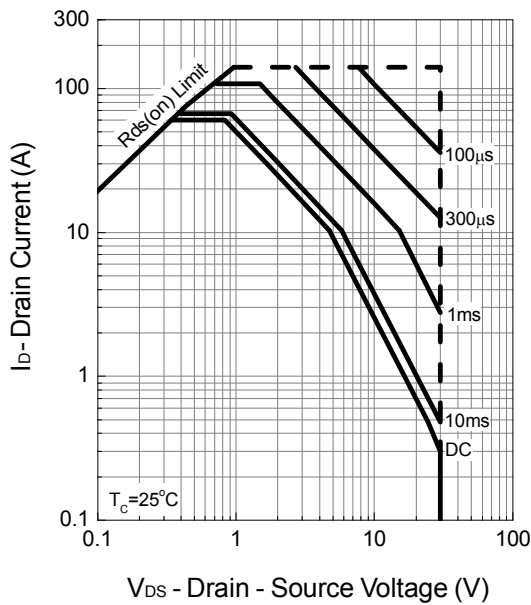
Power Dissipation



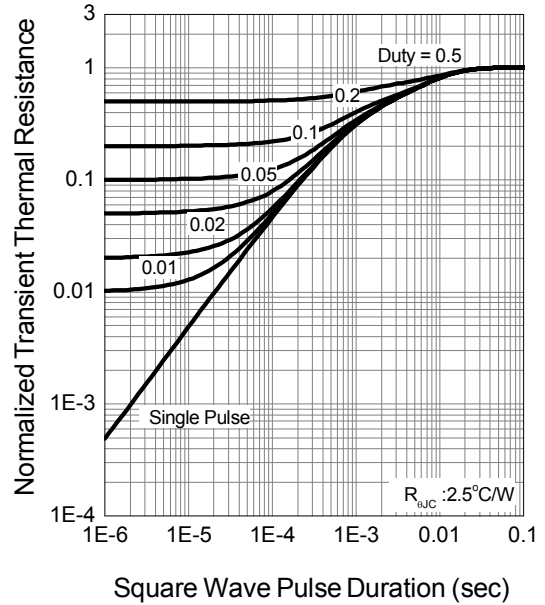
Drain Current



Safe Operation Area

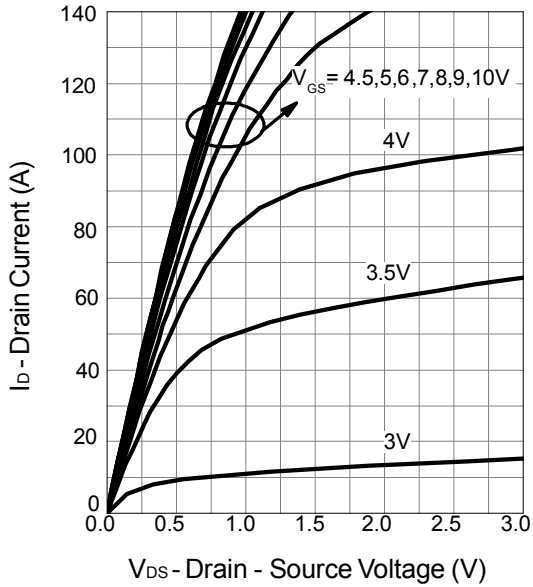


Thermal Transient Impedance

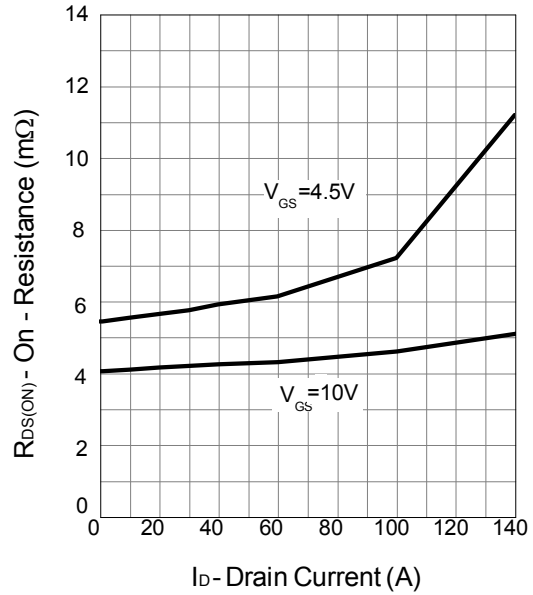


Typical Operating Characteristics (Cont.)

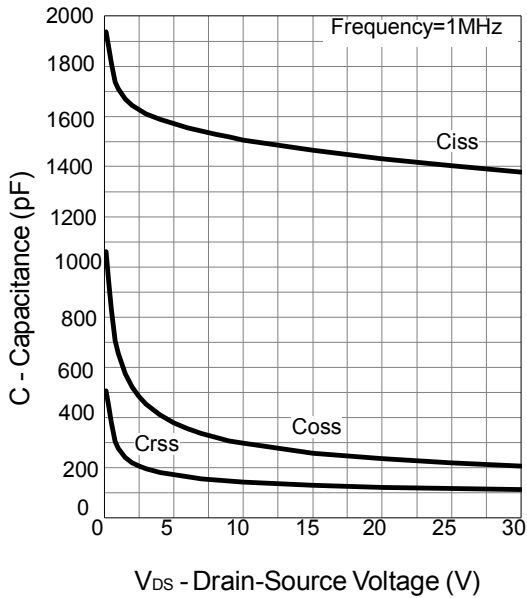
Output Characteristics



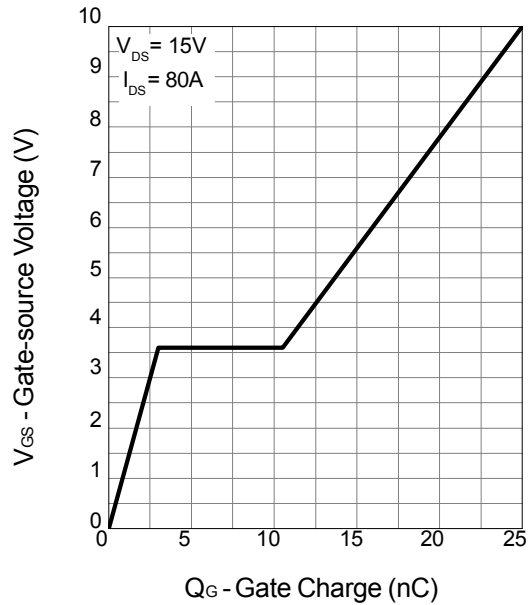
Drain-Source On Resistance



Capacitance

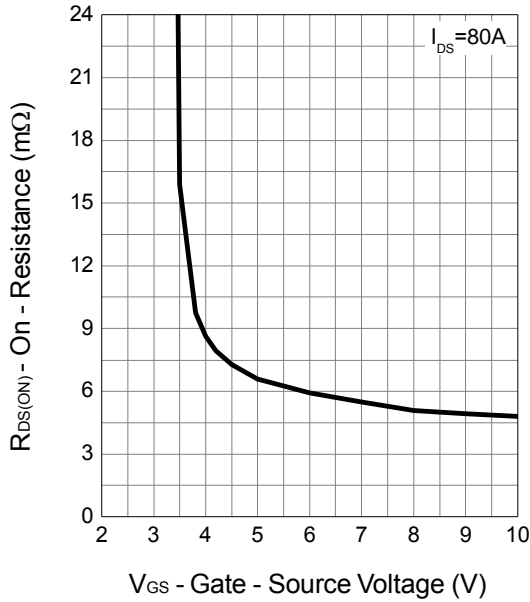


Gate Charge

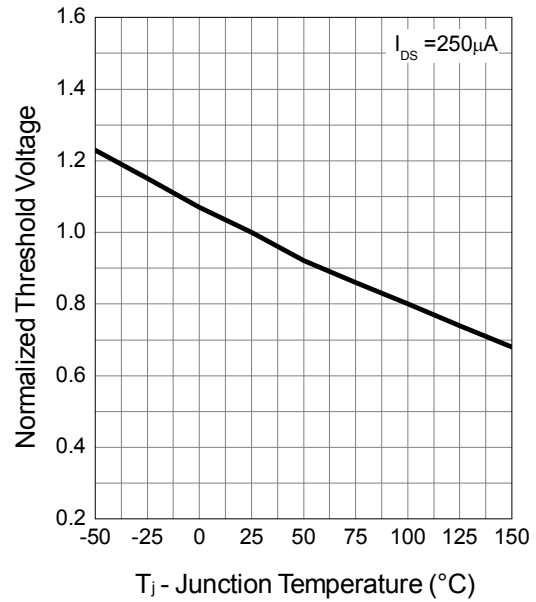


Typical Operating Characteristics (Cont.)

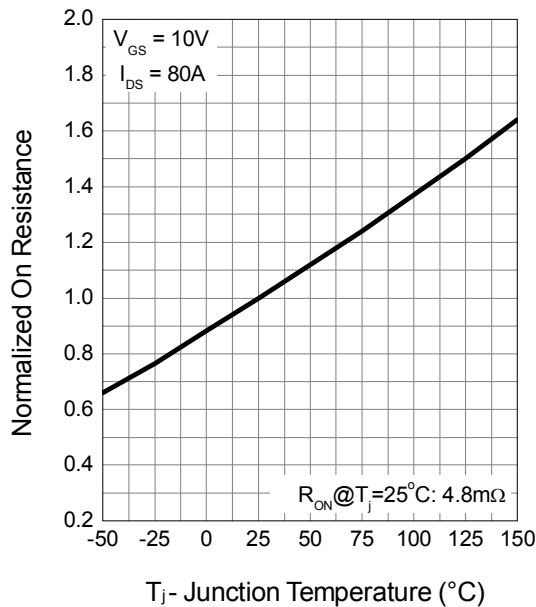
Gate-Source On Resistance



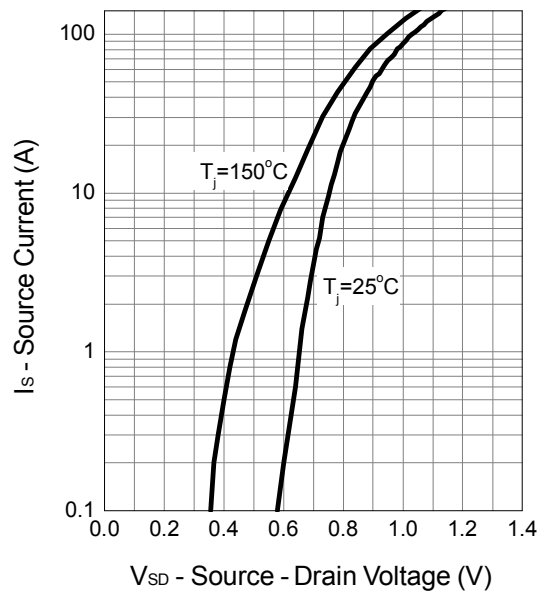
Gate Threshold Voltage



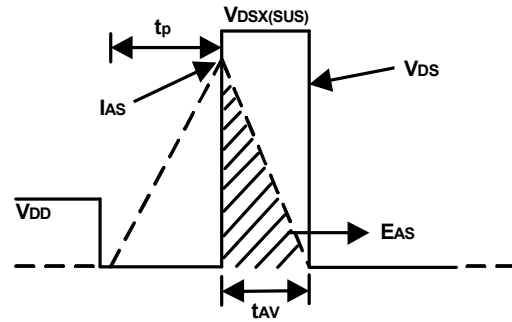
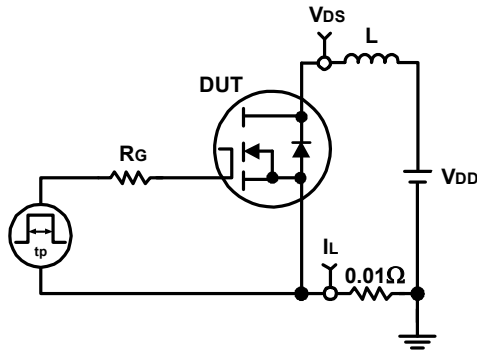
Drain-Source On Resistance



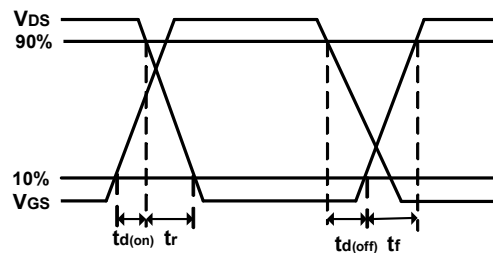
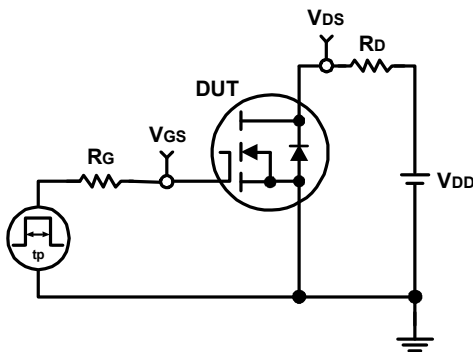
Source-Drain Diode Forward



Avalanche Test Circuit and Waveforms



Switching Time Test Circuit and Waveforms



Package Information
